

Notice of References Cited	Application/Control No. 10/573,444		Applicant(s)/Patent Under Reexamination SLATTER ET AL.	
	Examiner Brian Wilson		Art Unit 2612	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,442,348	08-1995	Mushell, Joshua	340/932.2
*	B	US-6,119,944	09-2000	Mulla et al.	235/472.03
*	C	US-2002/0047867	04-2002	Mault et al.	345/810
*	D	US-6,563,494	05-2003	Eichstaedt et al.	345/179
*	E	US-4,012,716	03-1977	Herrin, Carlos B.	235/462.19
*	F	US-4,750,151	06-1988	Baus, Heinz G.	700/90
*	G	US-6,002,387	12-1999	Ronkka et al.	345/157
*	H	US-6,346,885	02-2002	Curkendall, Leland D.	340/572.4
*	I	US-6,795,060	09-2004	Rekimoto et al.	345/173
*	J	US-7,110,576	09-2006	Norris et al.	382/119
*	K	US-7,456,826	11-2008	Jurisch et al.	345/179
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 09-034638	02-1997	Japan	Matsuda	G06F 3/033
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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